

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/727,060	SEKI ET AL.	
	Examiner	Art Unit	
	Thinh T. Nguyen	2818	

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>